



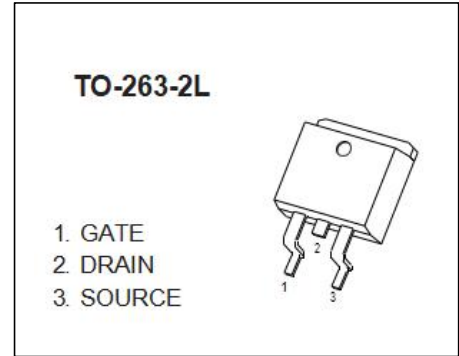
TO-263-2L Plastic-Encapsulate MOSFETS

CCMA160N10S N-Channel Power MOSFET

V_{DS}	$R_{DS(ON)}$ (Typ.)	I_D
100 V	3.5m Ω @10V	160A

DESCRIPTION

The CCMA160N10S provides excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.



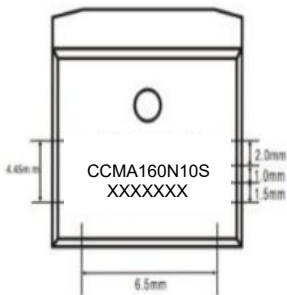
FEATURES

- Improved Gate, Avalanche and Dynamic dv/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- AEC Q101 Qualified

APPLICATIONS

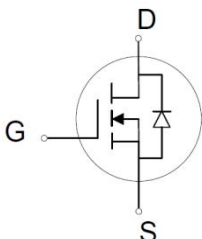
- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

MARKING



CCMA160N10S =Part No.
XXXXXXX = Code

EQUIVALENT CIRCUIT



ABSOLUTE MAXIMUM RATINGS($T_c=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 25	V
Continuous Drain Current	I_D	160	A
Pulsed Drain Current ¹	I_{DM}	640	A
Single Pulse Avalanche Energy ²	E_{AS}	300	mJ
Total Power Dissipation	P_D	250	W
Thermal Resistance from Junction to Case	$R_{\theta JC}$	0.6	$^{\circ}\text{C}/\text{W}$
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55~ +175	$^{\circ}\text{C}$
Soldering Temperature , for 10S(1.6mm from case)	-	260	$^{\circ}\text{C}$

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Limited by T_{Jmax} , starting $T_J = 25^{\circ}\text{C}$, $L = 0.033\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 135\text{A}$, $V_{GS} = 10\text{V}$. Part not recommended for use above 135A, although measured, the limit value of I_{AS} is 195A.

MOSFET ELECTRICAL CHARACTERISTICS

TC=25°C unless otherwise specified

Parameter	Symbol	Test Condition	Min	Type	Max	Unit
Off characteristics						
Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	100			V
Zero gate voltage drain current	I_{DSS}	$V_{DS} = 100V, V_{GS} = 0V$			1	μA
Gate-body leakage current	I_{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$			± 100	nA
On characteristics						
Gate threshold voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	3.0	4.0	V
Drain-source on-resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 1A$		3.5	4.0	m Ω
Transconductance	gfs	$V_{DS} = 10V, I_D = 10A$		46		S
Dynamic characteristics						
Input Capacitance	C_{iss}	$V_{DS} = 50V, V_{GS} = 0V, f = 1MHz$		5650		pF
Output Capacitance	C_{oss}			1200		
Reverse Transfer Capacitance	C_{rss}			43		
Gate resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		0.8		Ω
Switching characteristics¹						
Total Gate Charge	Q_g	$V_{DD} = 50V, V_{GS} = 10V, I_D = 75A$		105		nC
Gate-Source Charge	Q_{gs}			20		
Gate-Drain Charge	Q_{gd}			28		
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 50V, V_{GS} = 10V, I_D = 75A, R_G = 2.5\Omega$		28		ns
Turn-on rise time	t_r			32		
Turn-off delay time	$t_{d(off)}$			80		
Turn-off fall time	t_f			61		
Drain-source Diode characteristics						
Diode Forward Voltage ¹	V_{SD}	$V_{GS} = 0V, I_S = 75A, T_J = 25^\circ C$			1.3	V
Continuous Source Current ²	I_S	$T_c = 25^\circ C$			160	A
Pulsed drain-source diode forward current	I_{SM}	—			640	A
Reverse recovery time	t_{rr}	$V_{GS} = 0V, I_F = 10A, di/dt = 100A/\mu s$		85		ns
Reverse recovery charge	Q_{rr}			160		nC

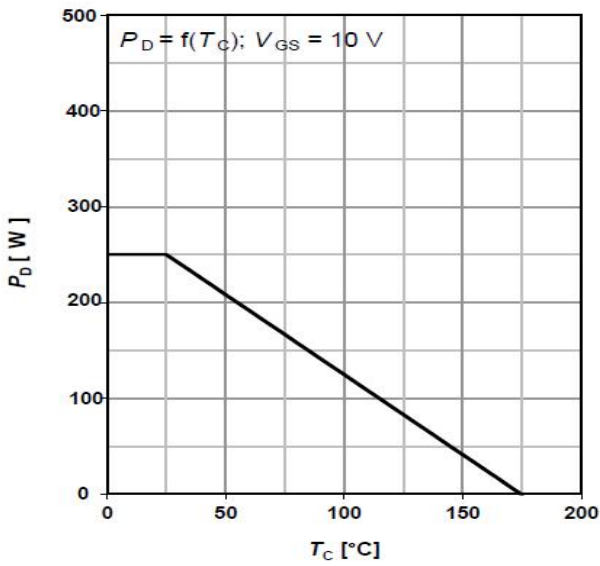
Note :

1. Pulse Test: Pulse Width $\leq 400\mu s$, Duty Cycle $\leq 2\%$.

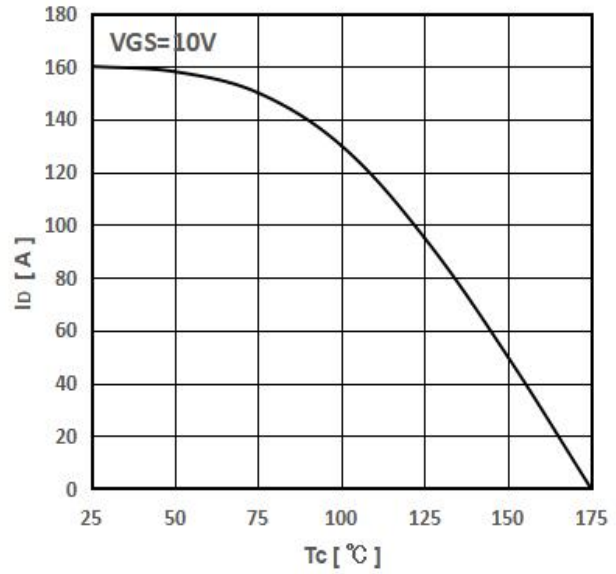
2. Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 120A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.

Typical Characteristics

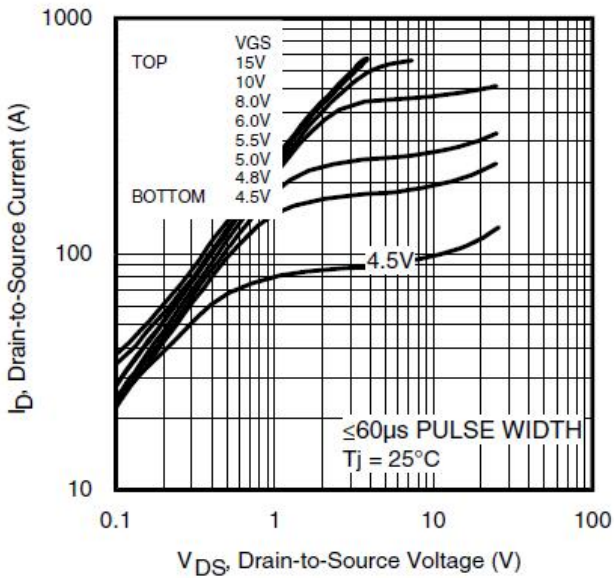
PD -- Tc



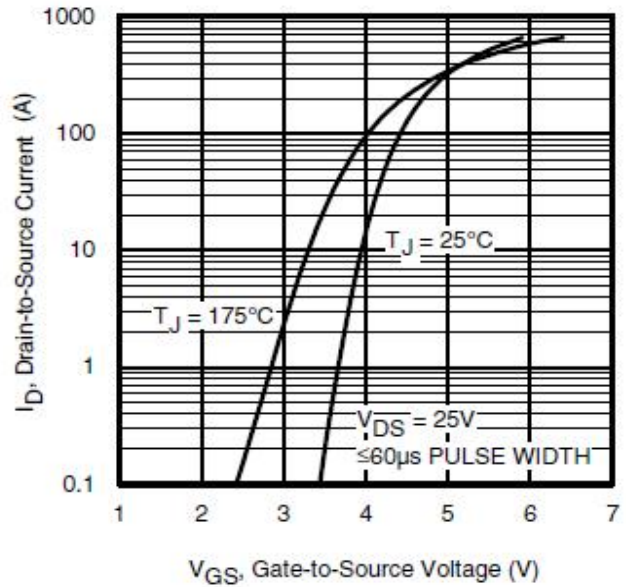
ID -- Tc



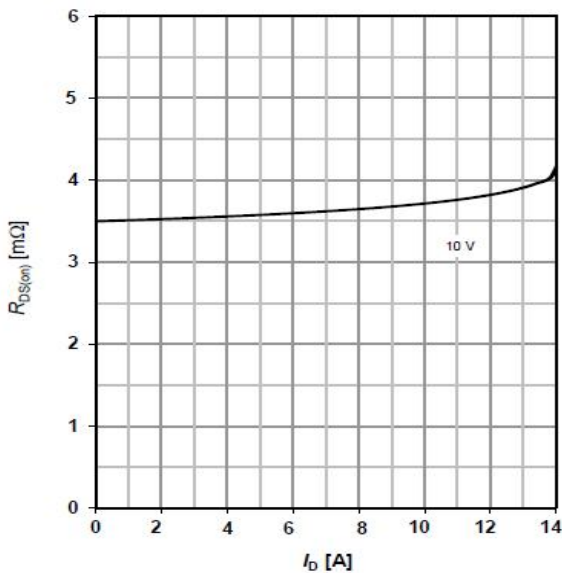
ID -- VDS



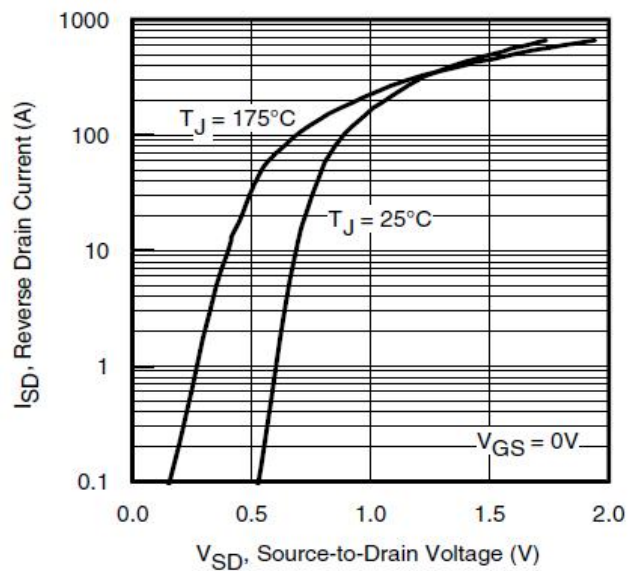
ID -- VGS



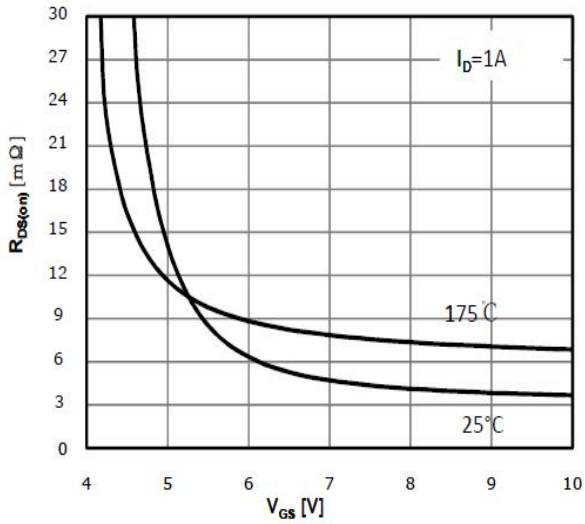
RDS(on) -- ID



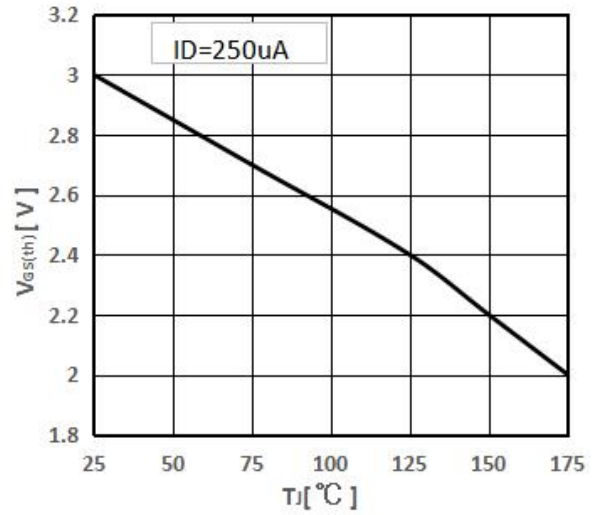
IS -- VSD



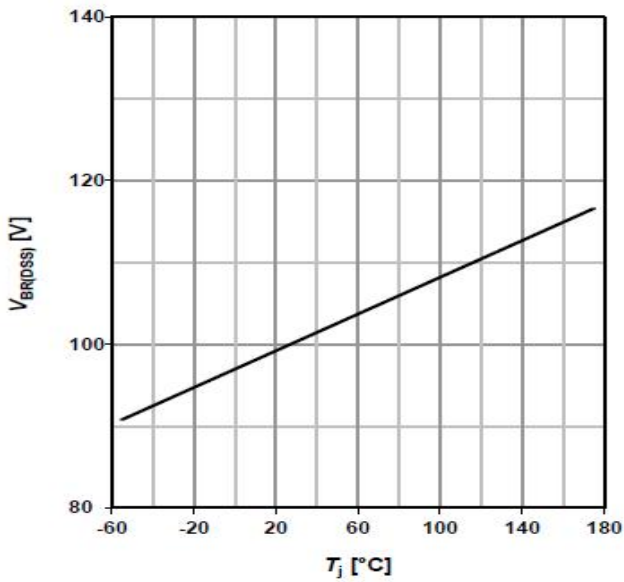
RDS(on) -- VGS



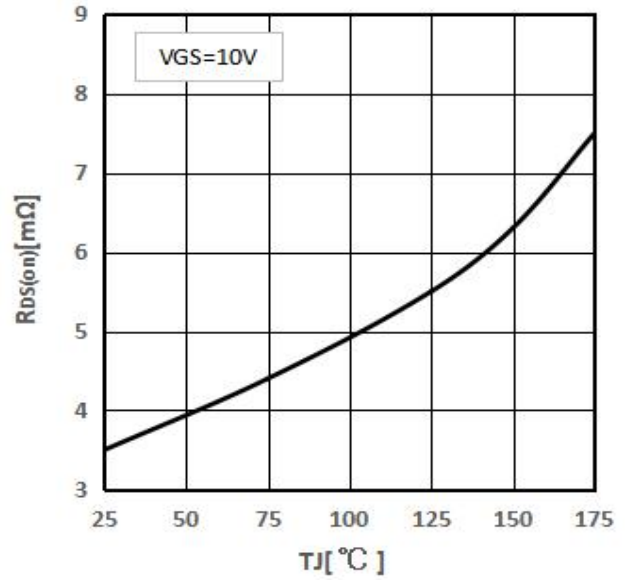
Threshold Voltage



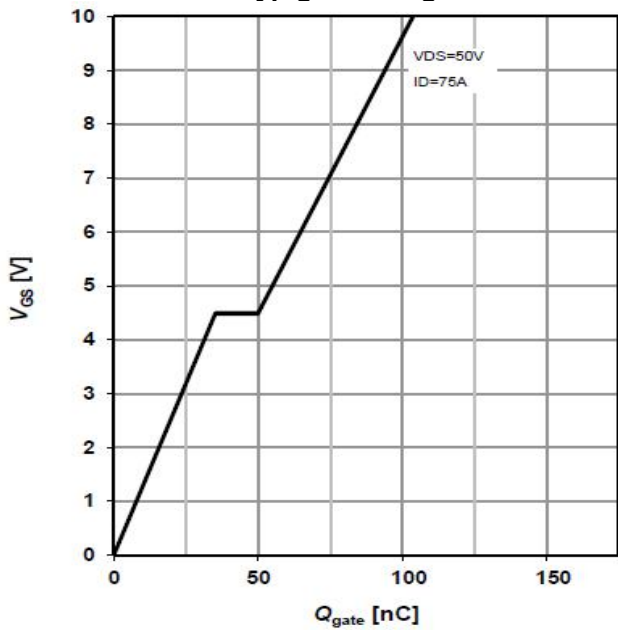
Drain-source breakdown voltage



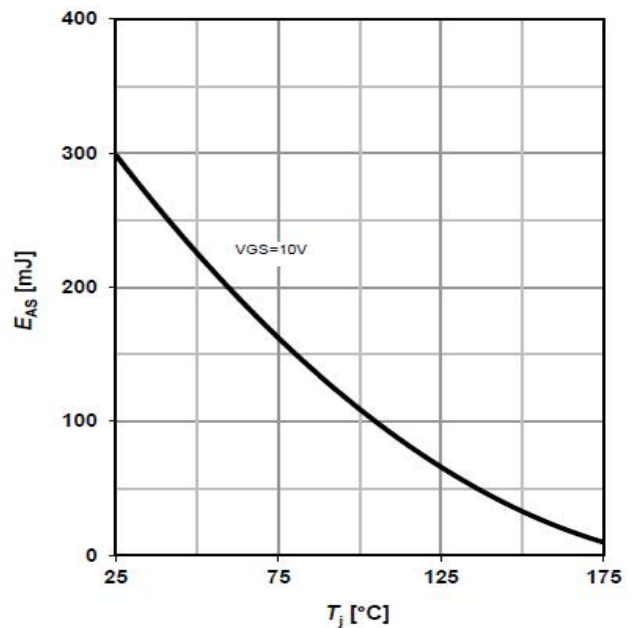
RDS (on) -- TJ



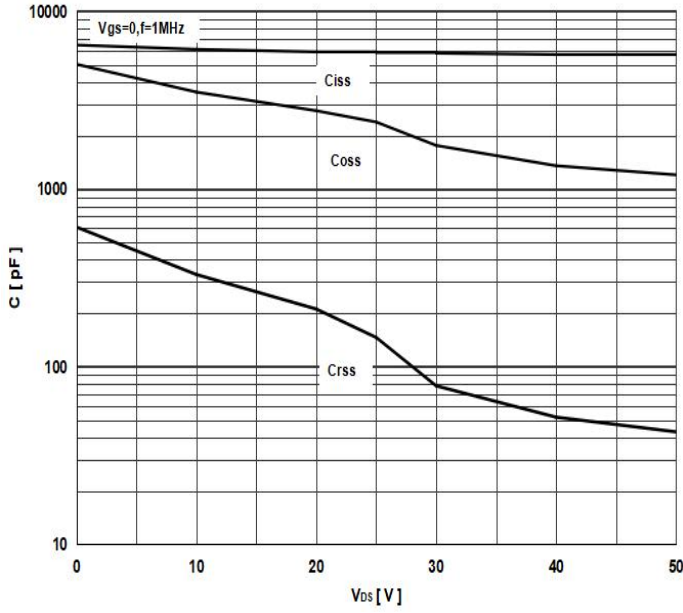
Typ.gate charge



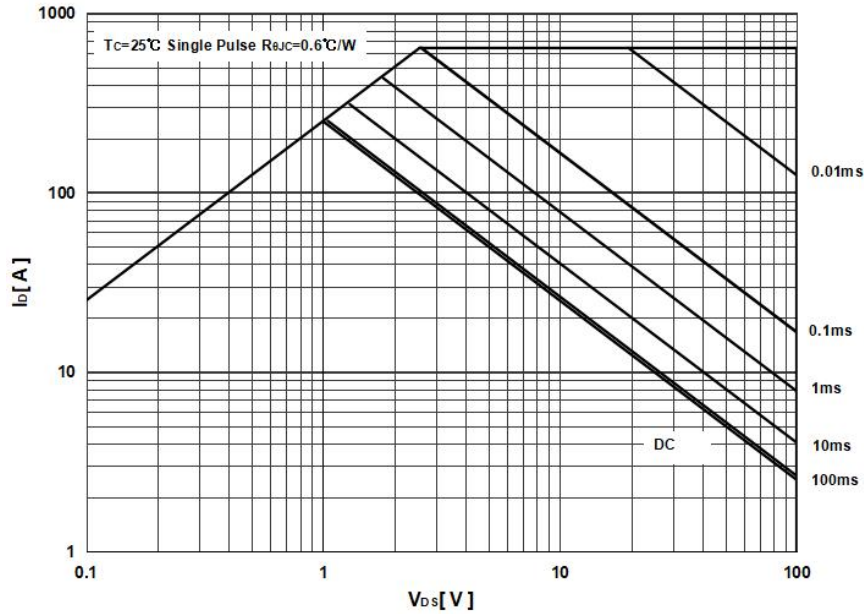
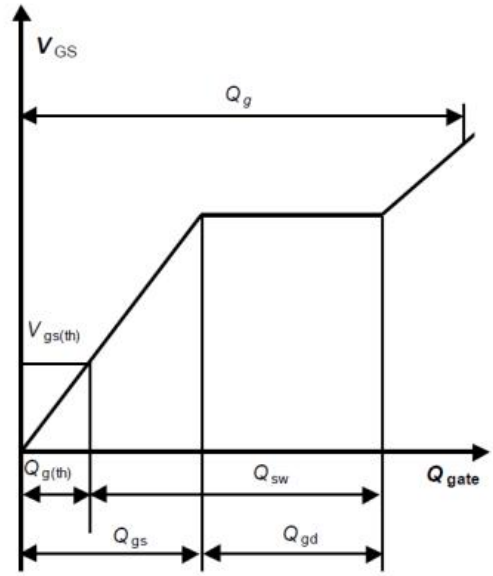
Avalanche energy



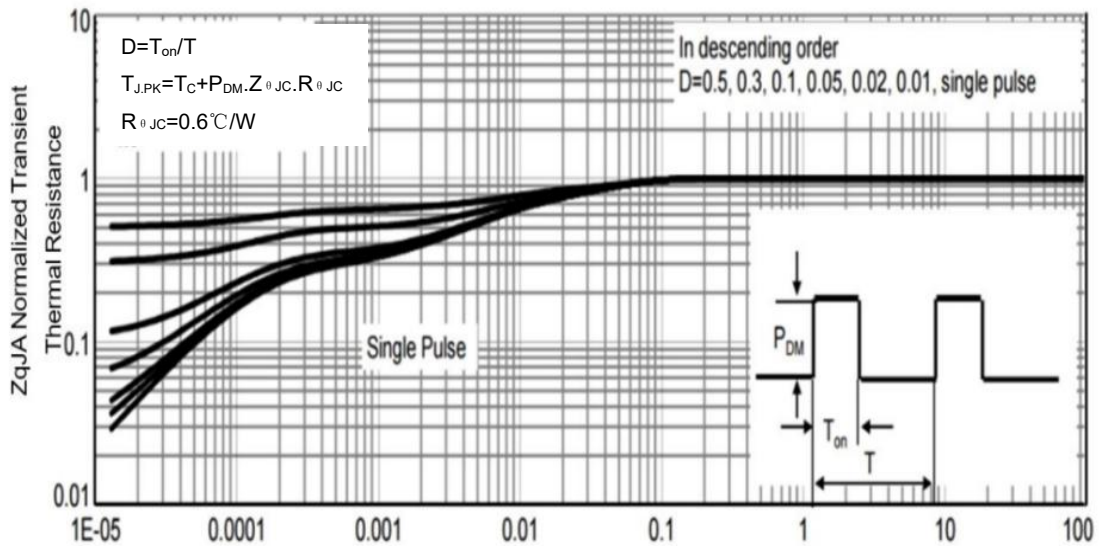
Typ. capacitance



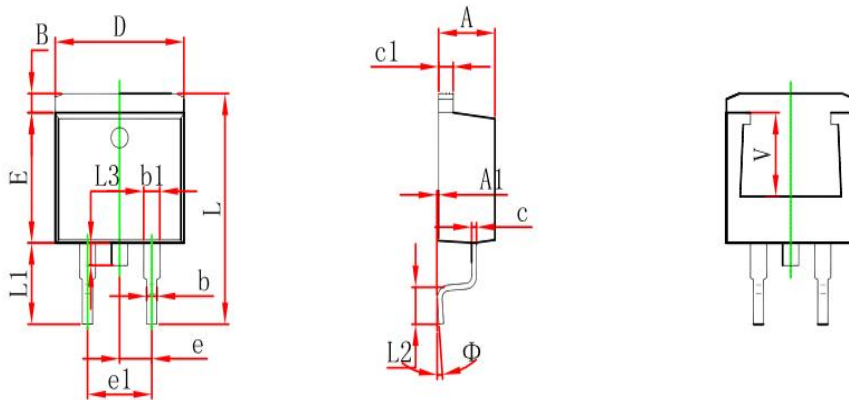
Gate charge waveforms



Normalized Thermal Transient Impedance

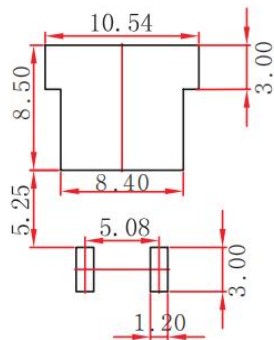


TO-263-2L Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.470	4.670	0.176	0.184
A1	0.000	0.150	0.000	0.006
B	1.120	1.420	0.044	0.056
b	0.710	0.910	0.028	0.036
b1	1.170	1.370	0.046	0.054
c	0.310	0.530	0.012	0.021
c1	1.170	1.370	0.046	0.054
D	10.010	10.310	0.394	0.406
E	8.500	8.900	0.335	0.350
e	2.540 TYP.		0.100 TYP.	
e1	4.980	5.180	0.196	0.204
L	14.940	15.500	0.588	0.610
L1	4.950	5.450	0.195	0.215
L2	2.340	2.740	0.092	0.108
L3	1.300	1.700	0.051	0.067
Φ	0°	8°	0°	8°
V	5.600 REF.		0.220REF.	

TO-263-2L Suggested Pad Layout



Note:

1. Controlling dimension: in millimeters.
2. General tolerance: 0.5mm.
3. The pad layout is for reference purposes only.

NOTICE

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Date of change	Rev #	revise content
2022/11/15	A/0	/